Artificial Intelligence in Effective Intrusion Detection for Clouds

Guest Editor:

Dr. Stavros Shiaeles
Cyber Security Research Group,
School of Computing University
of Portsmouth, Portsmouth PO1
2UP, UK

Deadline for manuscript
submissions:
31 December 2024

Message from the Guest Editor

The goal of this Special Issue is to bring together researchers and practitioners from academia and industry to explore recent advances, challenges, and opportunities in AI-driven intrusion detection for clouds. We invite original research articles and review papers that contribute to the development of innovative AI-based IDS solutions for cloud security. Topics include, but are not limited to, the following:

- Novel AI algorithms and models for intrusion detection in cloud environments;
- Integration of machine learning, deep learning, and data mining in IDS for clouds;
- Adaptive and self-learning IDS systems for dynamic cloud architectures;
- Big data analytics and anomaly detection for cloud security;
- AI-driven threat intelligence and risk assessment in cloud infrastructures;
- Performance evaluation and benchmarking of AI-based IDS solutions;
- Privacy-preserving techniques and ethical considerations in AI-driven intrusion detection;
- Case studies, practical implementations, and real-world applications of AI in cloud security.

Special Issue

Editor-in-Chief

Prof. Dr. Flavio Canavero
Department of Electronics and
Telecommunications,
Politecnico di Torino, 10129
Torino, Italy

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

Author Benefits

Open Access: free for readers, with article processing charges (APC) paid by authors or their institutions.
High Visibility: indexed within Scopus, SCIE (Web of Science), CAPlus / SciFinder, Inspec, and other databases.
Journal Rank: JCR - Q2(*Electrical and Electronic Engineering*) CiteScore - Q2 (*Electrical and Electronic Engineering*)

Contact Us